



# Mitsubishi Electric Semi-Conductors Division

## IGBT Module 7th Generation T-Series

June 14, 2018

14 juni 2018  
1931 Congrescentrum Den Bosch

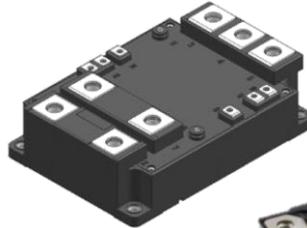
**POWER**  
**ELECTRONICS**

2018

## SLC-Technology (SoLid Cover Technology)

- Optimized structure with resin insulation
- Direct potting resin
- PC-TIM / PressFit available

LV100 package type



NX package type



std package type



## 7<sup>th</sup> chip technology

### Improved trade-off

- IGBT (CSTBT) (RFC)
- Diode

$V_{CEsat}$  vs  $E_{off}$   
 $dv/dt$  vs  $E_{off}$

$V_{EC}$  vs  $E_{rr}$   
 $dv/dt$  vs  $E_{rr}$

**Low loss & Low  $dv/dt$  device**

## TMS-Technology

### (Thick Metal Substrate)

- Optimized structure with  $Si_3N_4$  ceramic insulation
- Terminal US bonding
- PC-TIM available

# IGBT Module T Series with 7th Gen. IGBT 【NX type】

**NEW**

Some products are under development

## Point

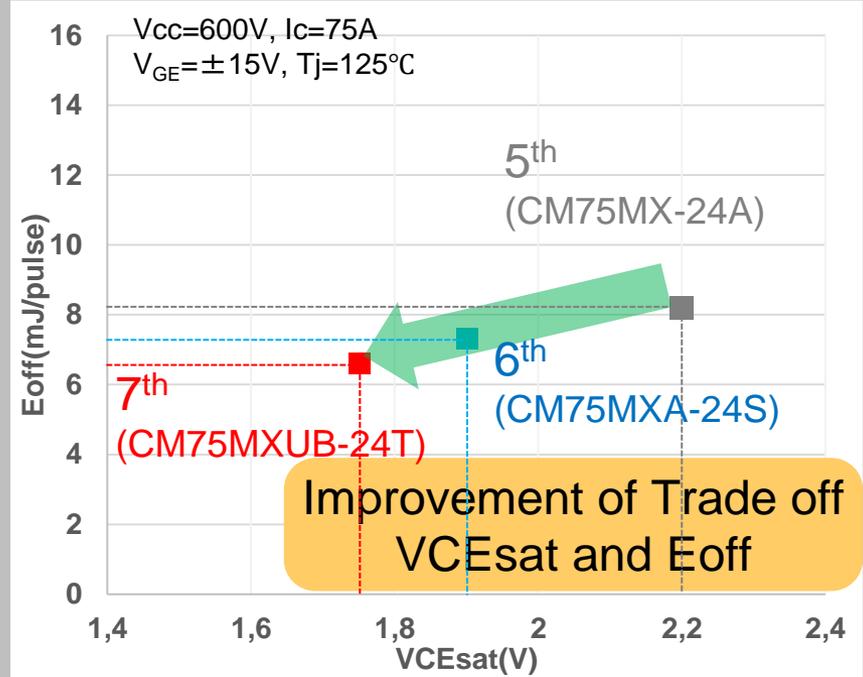
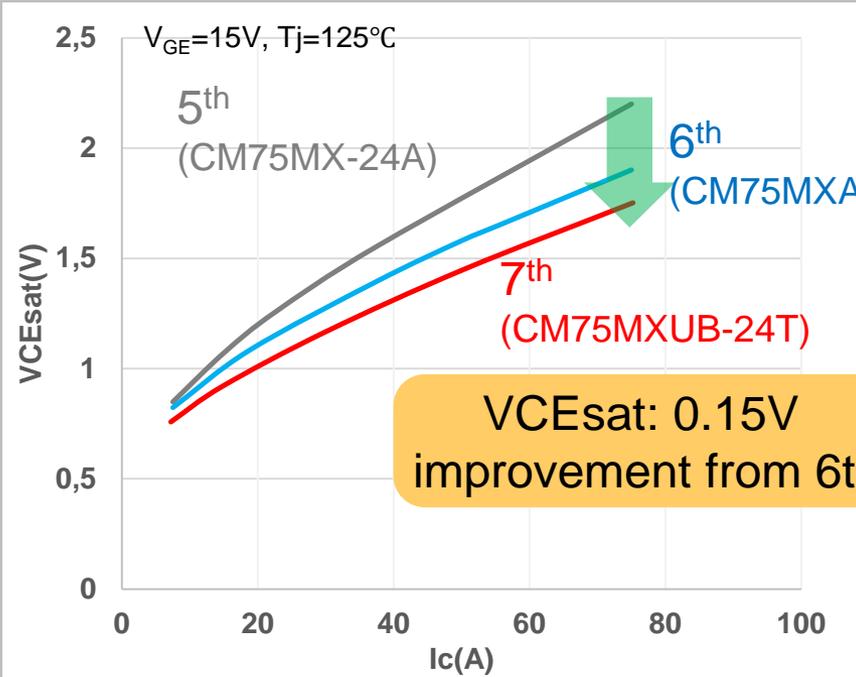
- ◆ New modules equipped with CIB\*, contributes to simplifying design.
- ◆ Significant improvement of Power loss
- ◆ High reliability
- ◆ Simplified assembly process



\* CIB: Converter, Inverter, and Brake circuit

VCES (V)	Connection	Current Rating (A)										
		35A	50A	75A	100A	150A	200A	225A	300A	450A	600A	1000A
650V	2 in1								●	●	●	
	6 in1				●	●	●					
	7 in1					●	●					
	C B		●	●	●	●						
1200V	2 in1							●	●	●	●	●
	6 in1				●	●	●					
	7 in1				●	●						
	C B	●	●	●	●	●						
1700V	2 in1							●	●	●	●	
	6 in1				●	●						

# Significant improvement of Power loss



**Power loss is reduced with 7th-Gen. IGBT**

# High reliability

- ◆ 7<sup>th</sup> -generation chips lead better trade-off characteristics and lower loss
- ◆ New package technologies realize High reliability and Light weight
- ◆ Press-Fit pins and PC-TIM\* achieve easy mounting

## ■ Outlook

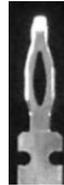


## ■ Features

- High Reliability
- Compatible with 6<sup>th</sup> Gen. NX type
- **Press-Fit pins available**

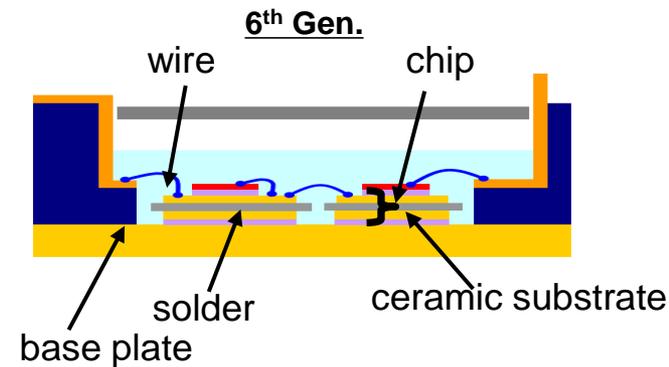


Power terminals

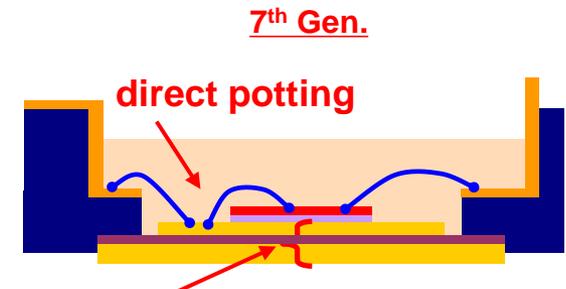
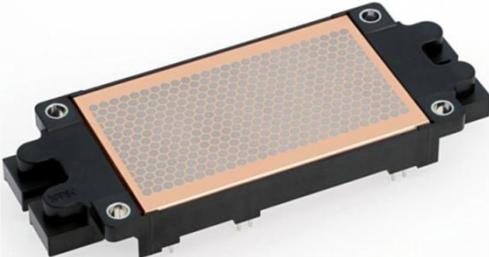


Auxiliary terminals

## ■ Package structure comparison



## ■ Pre-applied PC-TIM\*

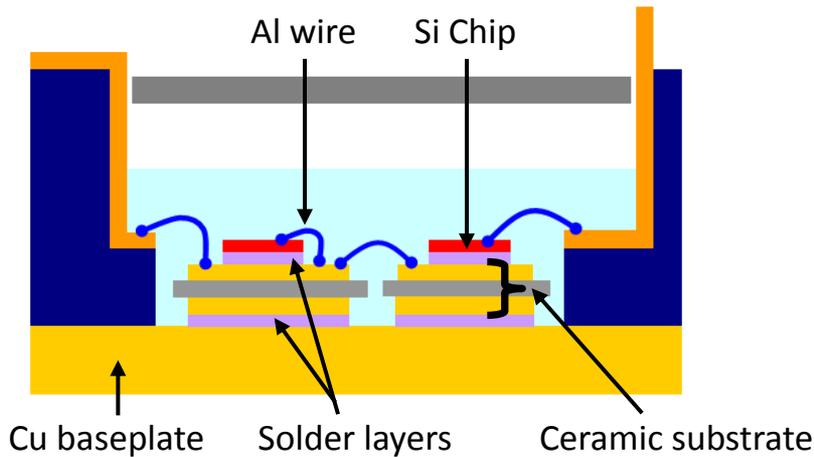


**Insulated Metal Base-plate structure**

\*PC-TIM: Phase Change - Thermal Interface Material

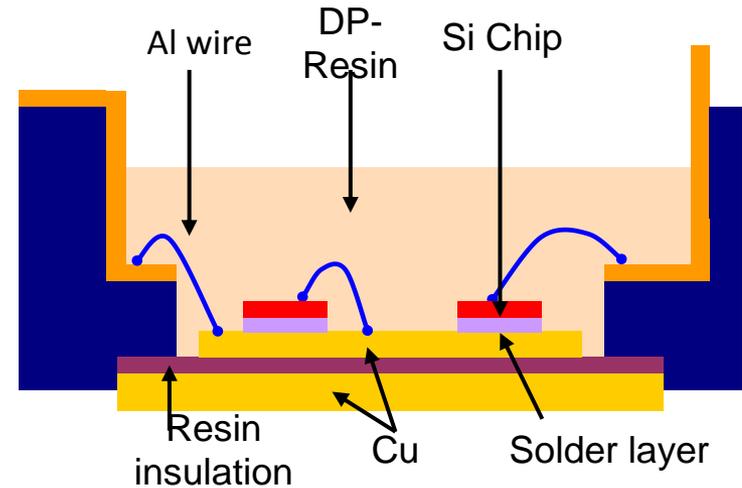
NX/LV100 type

## Conventional



Material	CTE* [ppm/K]
Al wire	23
Si Chip	2.3
Ceramic substrate	4.5 ~ 7.0
Cu baseplate	≈17

## SLC-Technology



Material	CTE* [ppm/K]
Al wire	23
Si Chip	2.3
Cu, Resin	≈17

CTE\* = Coefficient of Thermal Expansion

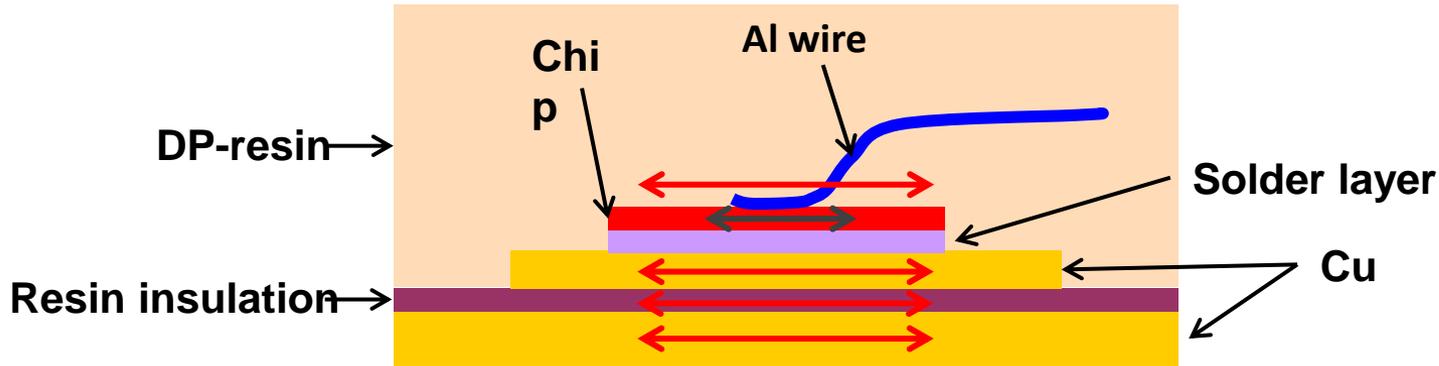
➤ **Matching thermal expansion of copper and resin**

# Matched Thermal Expansion

NX type

## SLC-Technology

CTE\* = Coefficient of Thermal Expansion



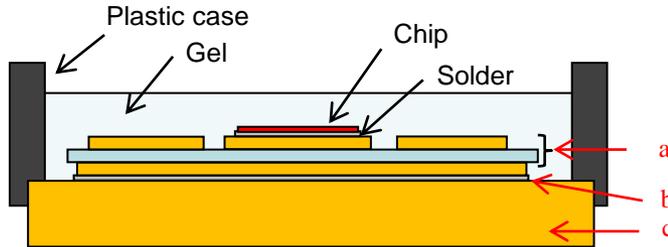
CTE\*: Copper ≈ Resin

SLC-Technology structure stress concentrates between different CTE of chip, solder, Al wire and decreases strain of each elements

- Reduced baseplate warpage  
→ reduced pumping out

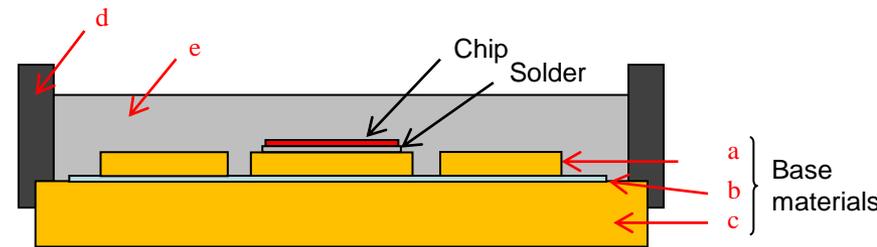
NX type

## Conventional



Symbol	a	b	c
Material	DBC	Solder	Copper
CTE(10 <sup>-6</sup> /K)	6.9	26	16.7

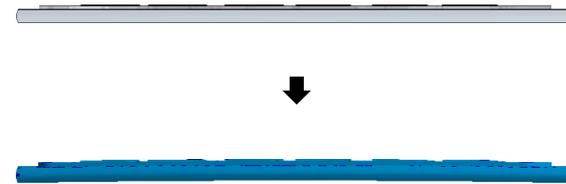
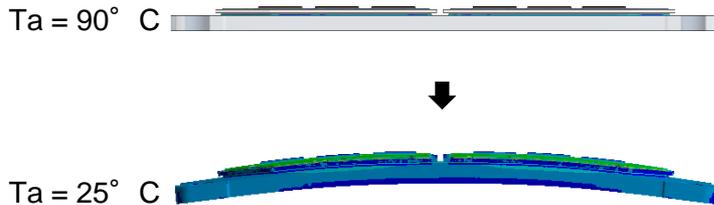
## SLC-Technology



Symbol	a	b	c	d	e
Material	Copper	Insulator	Copper	Plastic	Resin
CTE (10 <sup>-6</sup> /K)	16.7	16.7	16.7	16.5	16.0

CTE of components

Simulation



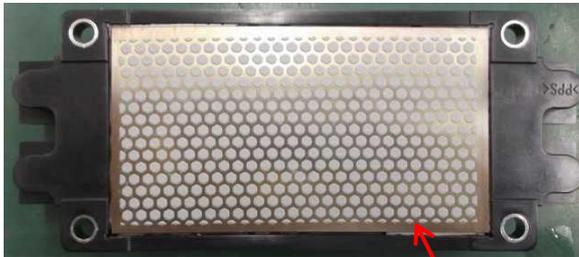
\*10 times amplified image

- Practically no pumping out of thermal interface material
- Improved reliability of Rth(c-s) which results in improved overall reliability

# Simplified assembly process (NX type/std type)

## PC-TIM support

- Delivered product  
Solid in room temp.



**PC-TIM**

## <ADVANTAGES>

- Easier to handle than thermal grease
- Save grease applied process at assembly
- Superior thermal conductivity owing to high heat dissipation material and strict thickness control

- After phase changed (during operation)  
Get softened and expand same as thermal grease

※ Pre-application of PC-TIM is applicable to both std-type and NX-type products.



Mounted on glass for observation

PC-TIM: Phase Change – Thermal Interface Material

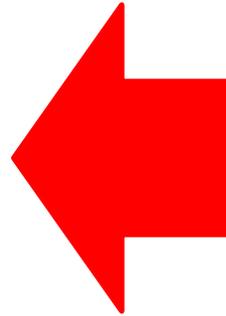
**PC-TIM contribute to simplifying the assemble process**

# Converter + Brake + Inverter

Approx. 36%  
size reduction



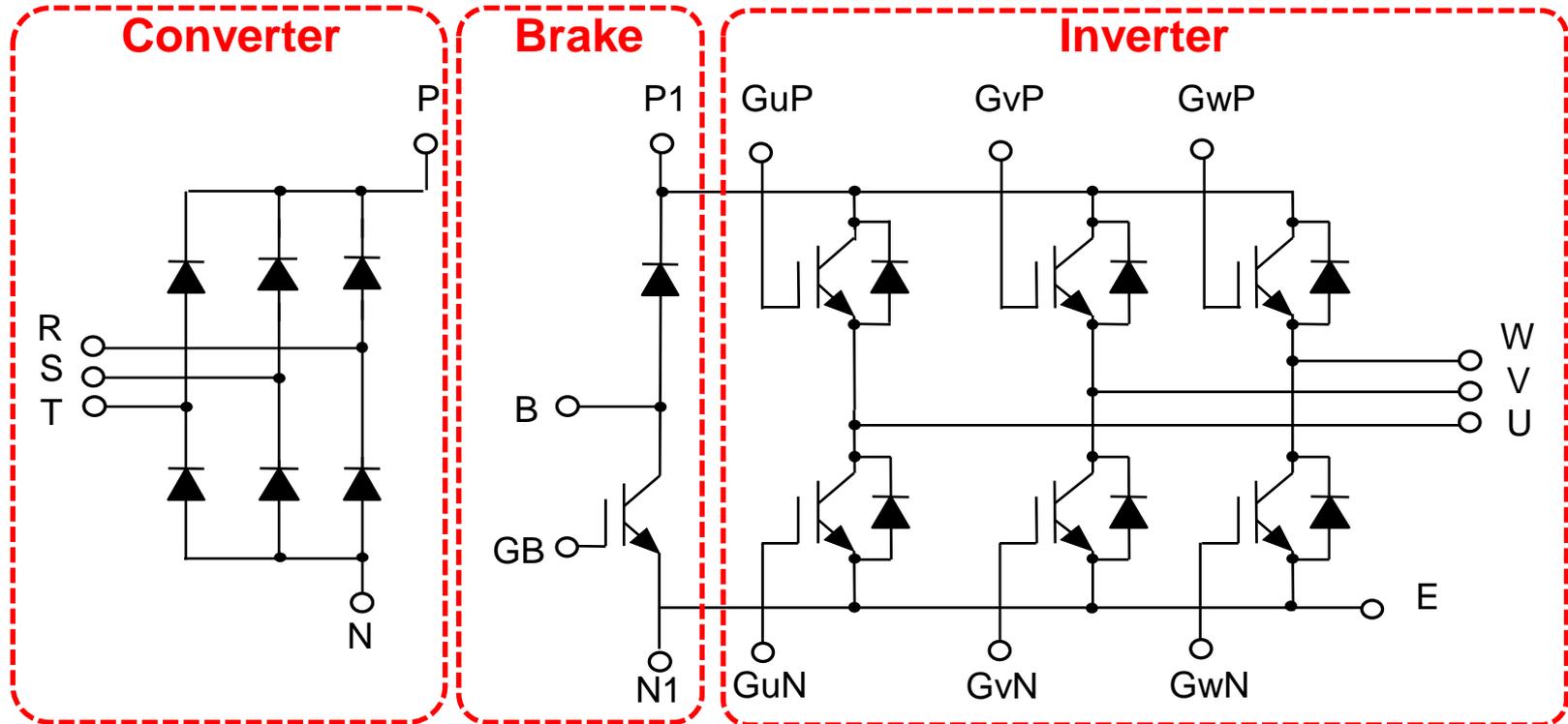
**CIB Module**  
(75A/1200V CIB-S package)



IGBT Module S/S1 series  
(75A/1200V CIB-M package)

 Smaller, simpler design for inverter systems

# Converter + Brake + Inverter



 Smaller, simpler design for inverter systems

# IGBT Module T Series with 7<sup>th</sup> Gen. IGBT [std type]

**NEW**

Some products are under development



## Point

- ◆ Significant improvement of Power loss
- ◆ High reliability/Compact and Light weight
- ◆ Simplified assembly process



VCES (V)	conecction	Current Rating (A)							
		75A	100A	150A	200A	300A	400A	450A	600A
650V	2 in 1		●	●	●	●	●		●
1200V			●	●	●	●		●	●
1700V		●	●	●	●	●	●		

# High reliability/Compact and Light weight

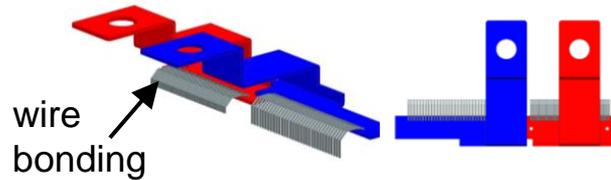
◆ New package technologies realize Low internal inductance, High reliability, Compact, and Light weight

■ Outlook



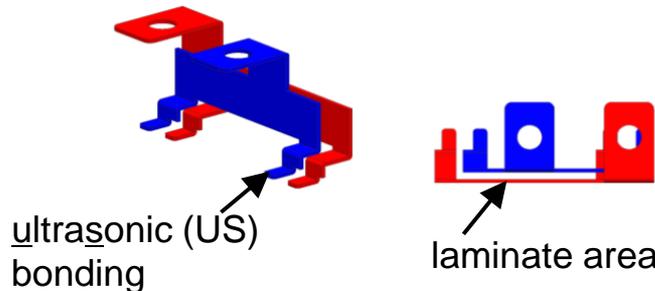
■ Package inductance

Main terminals of 6<sup>th</sup> Gen.



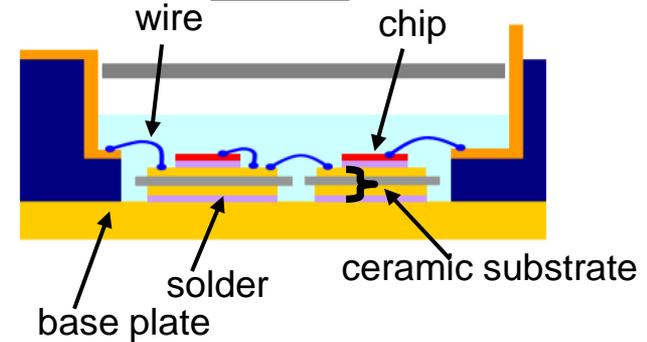
**Approx. 30% reduction**

Main terminals of 7<sup>th</sup> Gen.

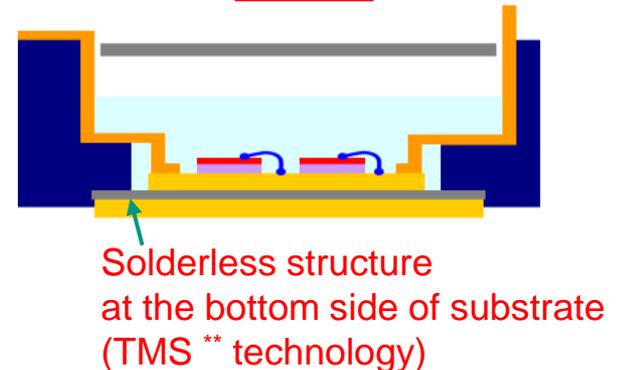


■ Package structure comparison

6<sup>th</sup> Gen.



7<sup>th</sup> Gen.



■ Pre-applied PC-TIM\*

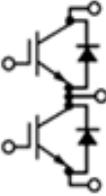


\*PC-TIM: Phase Change - Thermal Interface Material

\*\*TMS: Thick Metal Substrate

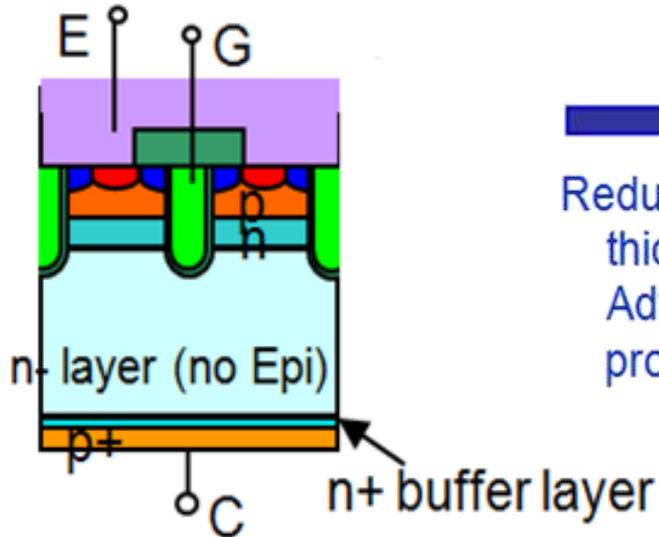
## LV100-type

### Rated Current I<sub>c</sub> [A]

Circuit	Topology	Package outline	Package size	1200V	1700V
2in1	D			100mm x 140mm	t.b.d.
					800A
					1200A

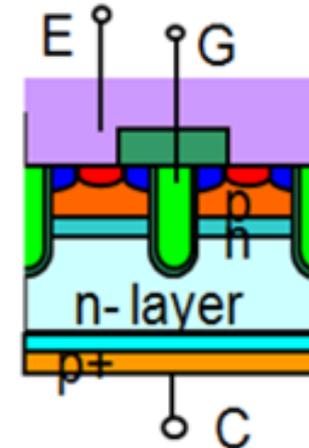
## ■ Cross sectional structure

### Conventional



➔  
Reduced wafer thickness,  
Advanced processes

### 7<sup>th</sup> generation



### Keys

#### 1. Thinner N<sup>-</sup> drift layer

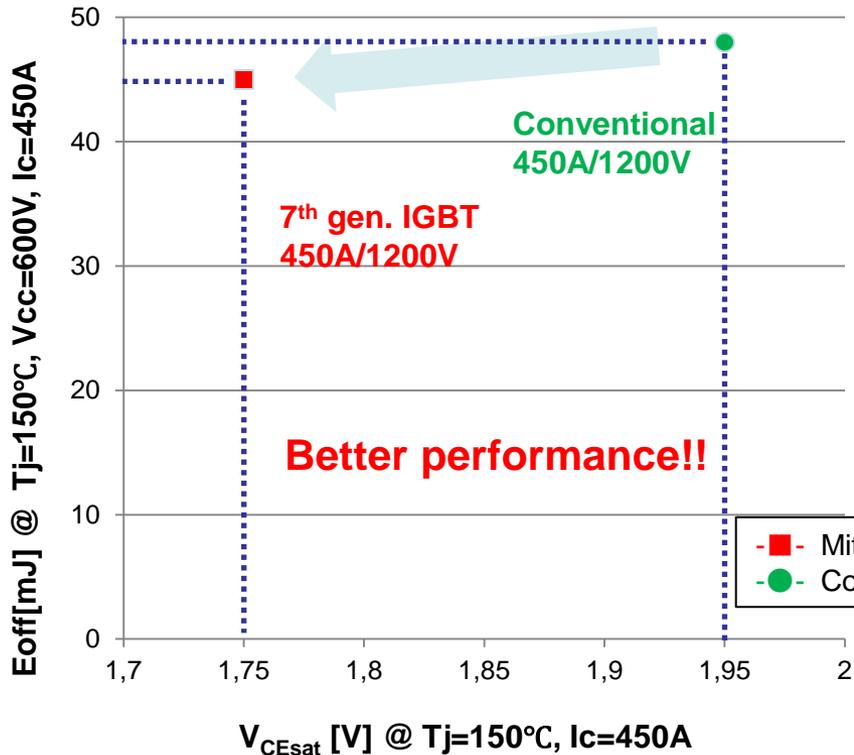
Low  $V_{CEsat}$

Low  $E_{off}$

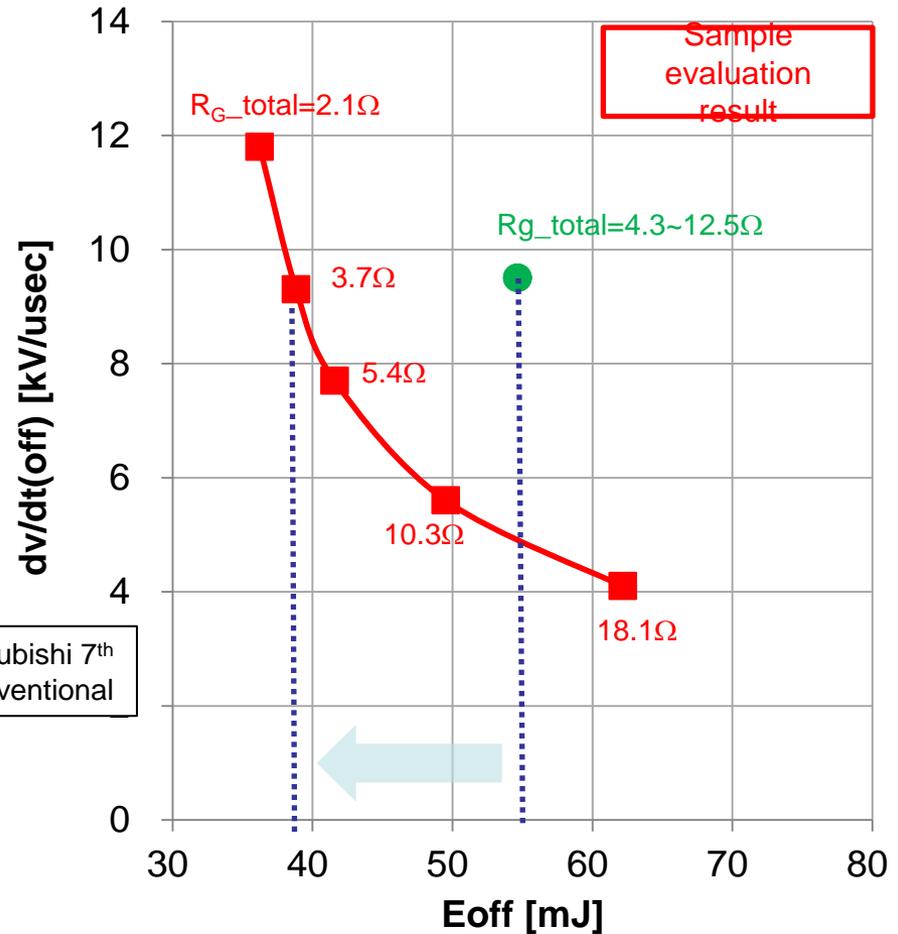
#### 2. Optimized cell design

Better controllability of  $dv/dt$  with  $R_G$

## ■ $V_{CEsat}$ vs $E_{off}$ trade-off



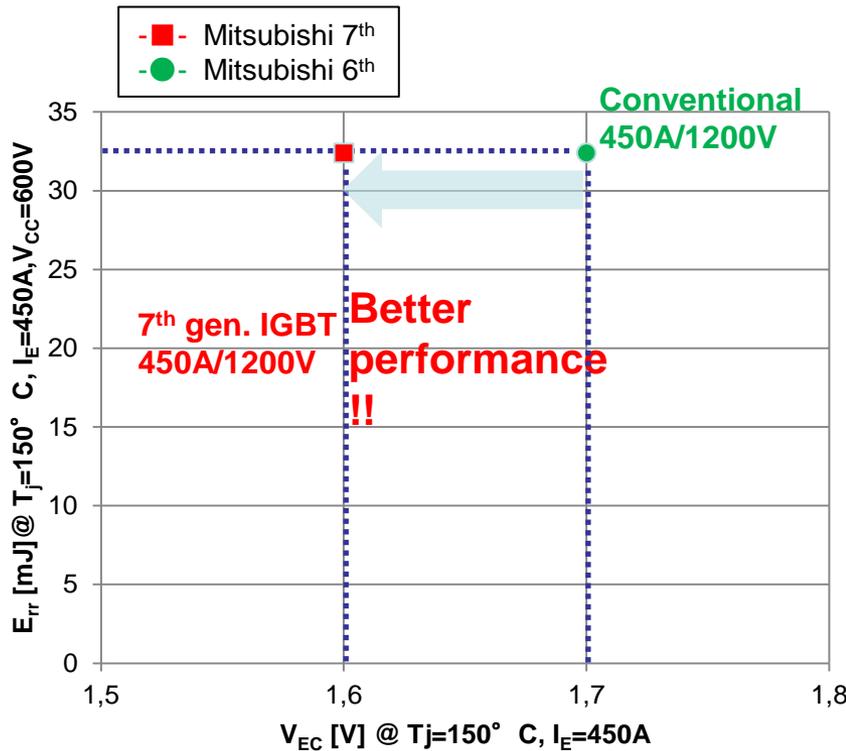
## ■ $E_{off}$ vs $dv/dt$ (off) trade-off



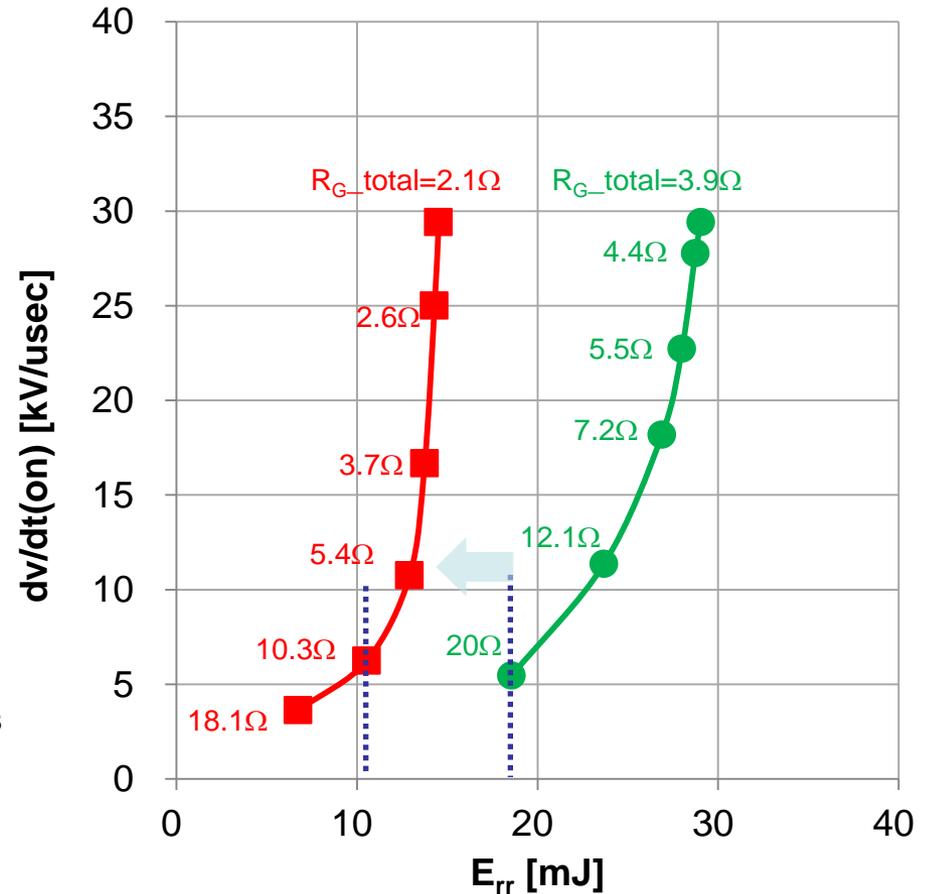
7<sup>th</sup> gen. IGBT has better static and dynamic characteristics. It also has better controllability of  $dv/dt$  with  $R_G$ .

Sample evaluation result

## $V_{EC}$ vs $E_{rr}$ trade-off



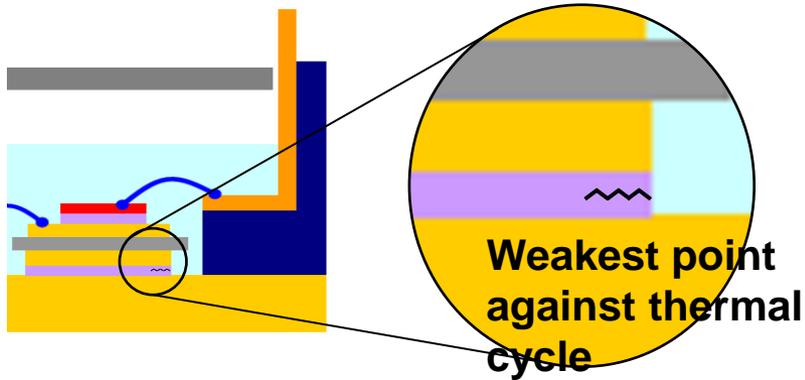
## $E_{rr}$ vs $dv/dt$ (rec) trade-off



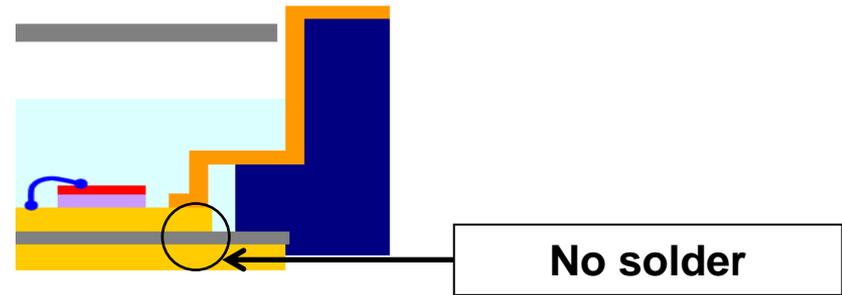
RFC diode improves the  $E_{rr}$  vs.  $V_{EC}$  trade-off from 6<sup>th</sup> gen. Diode. Err against  $dv/dt$  is further reduced than the other diodes.

**std type**

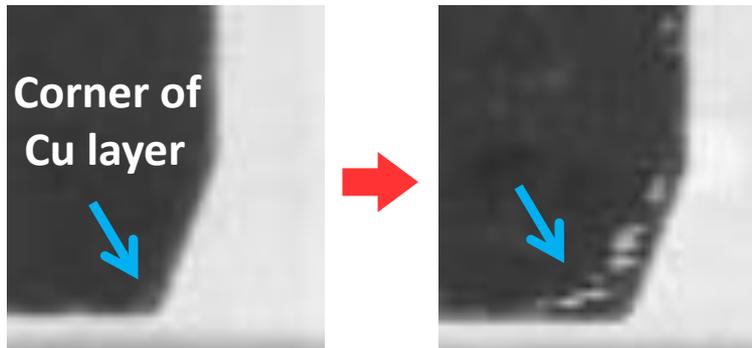
**Conventional**



**TMS**

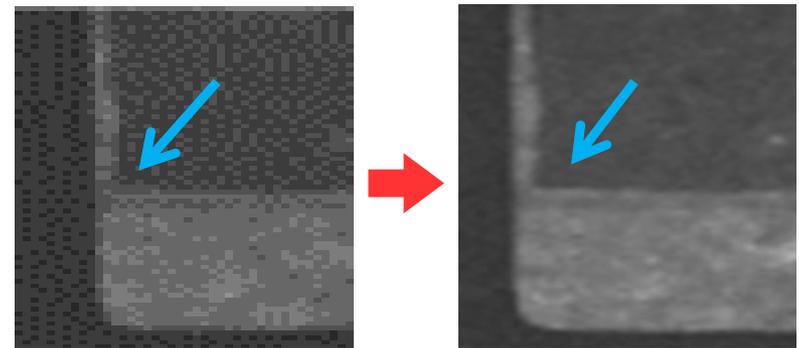


■ Temperature cycling test (-40°C ~ 125°C)



**Before test**

**After 300cyc.**



**Before test**

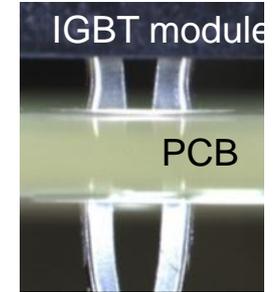
**After 1000cyc.**

➤ **No crack until 1000cyc. → more than 3 times higher capability**

NX type

## Main terminals

	Market standard	MITSUBISHI (6in1)
Shape		
Press-in force	75-81N/pin	76N/pin
Press-out force	59-64N/pin	50N/pin

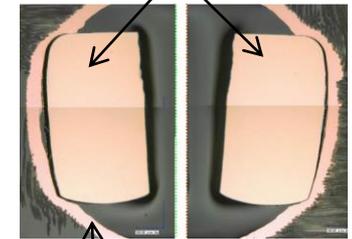


Press fit main terminal

## Auxiliary terminals

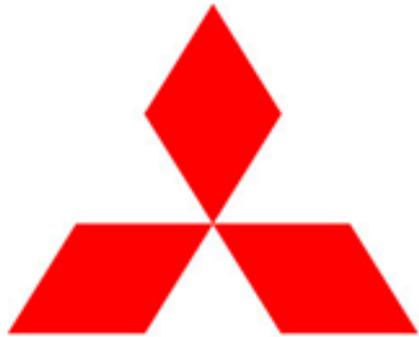
	Market standard	MITSUBISHI (2in1)
Shape	 	
Press-in force	110N/pin (typ.)	100N/pin (typ.)
Press-out force	n/d	40N/pin

Press fit terminals



Plated through-hole

- **The same requirement as market standard** (PCB material, thickness and hole diameter)
- **Improved reliability and reduced contact resistance**



**MITSUBISHI  
ELECTRIC**

*Changes for the Better*

**GLYN**

14 juni 2018  
1931 Congrescentrum Den Bosch

**POWER  
ELECTRONICS**

**2018**